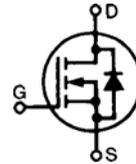
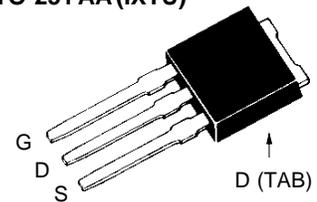
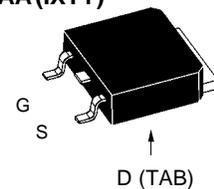


High Voltage MOSFET

N-Channel, Enhancement Mode

IXTU 01N80
IXTY 01N80
 $V_{DSS} = 800 \text{ V}$
 $I_{D25} = 100 \text{ mA}$
 $R_{DS(on)} = 50 \ \Omega$


Symbol	Test Conditions	Maximum Ratings 01N100	
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	800	V
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1 \text{ M}\Omega$	800	V
V_{GS}	Continuous	± 20	V
V_{GSM}	Transient	± 30	V
I_{D25}	$T_C = 25^\circ\text{C}$; $T_J = 25^\circ\text{C}$ to 150°C	100	mA
I_{DM}	$T_C = 25^\circ\text{C}$, pulse width limited by max. T_J	400	mA
P_D	$T_C = 25^\circ\text{C}$	25	W
T_J		-55 ... +150	$^\circ\text{C}$
T_{JM}		150	$^\circ\text{C}$
T_{stg}		-55 ... +150	$^\circ\text{C}$
T_L	1.6 mm (0.063 in) from case for 5 s	300	$^\circ\text{C}$
Weight		0.8	g

TO-251 AA (IXTU)

TO-252 AA (IXTY)


G = Gate, D = Drain,
 S = Source, TAB = Drain

Symbol	Test Conditions	Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)		
		min.	typ.	max.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 25 \ \mu\text{A}$	800		V V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 25 \ \mu\text{A}$	2		4.5 V
I_{GSS}	$V_{GS} = \pm 20 \text{ V}_{DC}$, $V_{DS} = 0$			$\pm 50 \text{ nA}$
I_{DSS}	$V_{DS} = 0.8 \cdot V_{DSS}$, $T_J = 25^\circ\text{C}$ $V_{GS} = 0 \text{ V}$, $T_J = 125^\circ\text{C}$			10 μA 200 μA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = I_{D25}$ Pulse test, $t \leq 300 \text{ ms}$, duty cycle $d \leq 2 \%$			50 Ω

Features

- International standard packages
JEDEC TO-251 AA, TO-252 AA
- Low $R_{DS(on)}$ HDMOS process
- Rugged polysilicon gate cell structure
- Fast switching times

Applications

- Level shifting
- Triggers
- Solid state relays
- Current regulators

